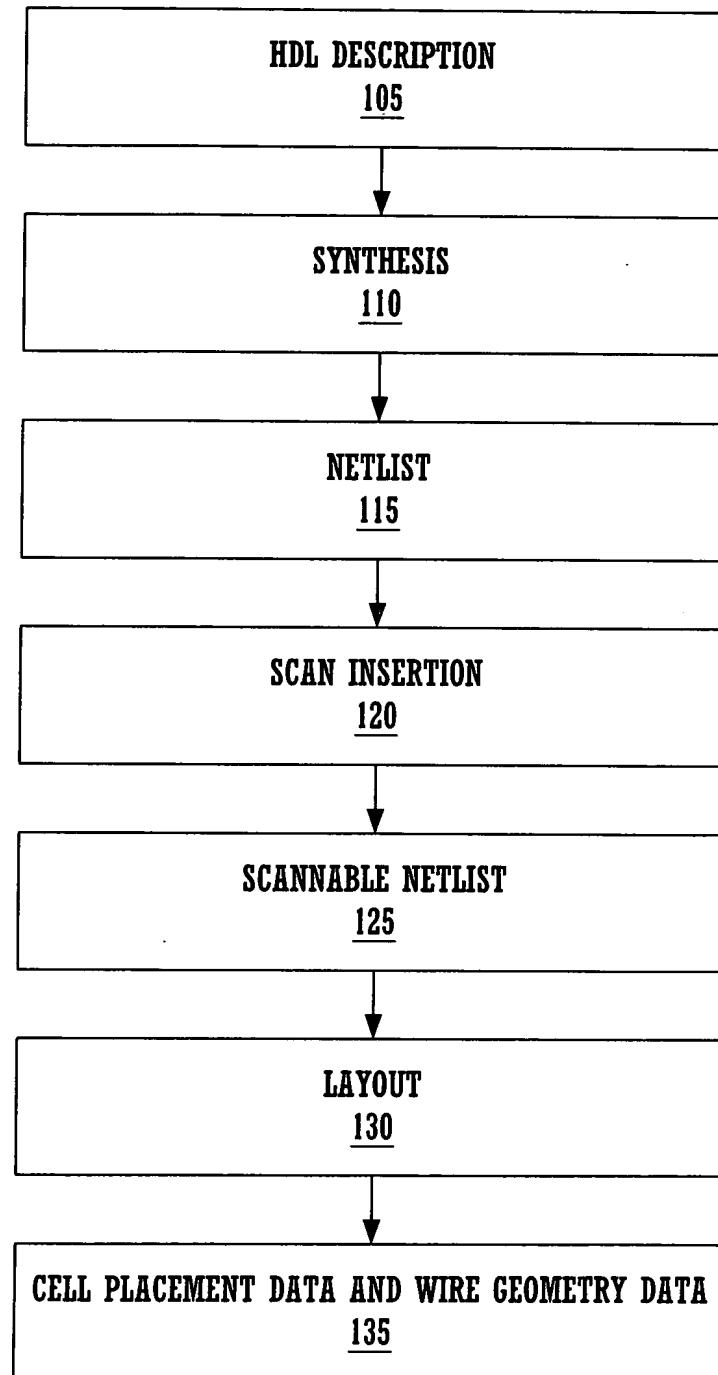


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TITLE: SYSTEM AND METHOD FOR HIGH-LEVEL TEST PLANNING FOR LAYOUT  
INVENTOR(S): Suryanarayana Duggirala, Rohit Kapur, Thomas W. Williams  
Attorney Docket #: SNSY-A1998-035

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**FIGURE 1**  
(Prior Art)

TITLE: SYSTEM AND METHOD FOR HIGH-LEVEL TEST PLANNING FOR LAYOUT  
INVENTOR(S): Suryanarayana Duggirala, Rohit Kapur, Thomas W. Williams  
Attorney Docket #: SNSY-A1998-035

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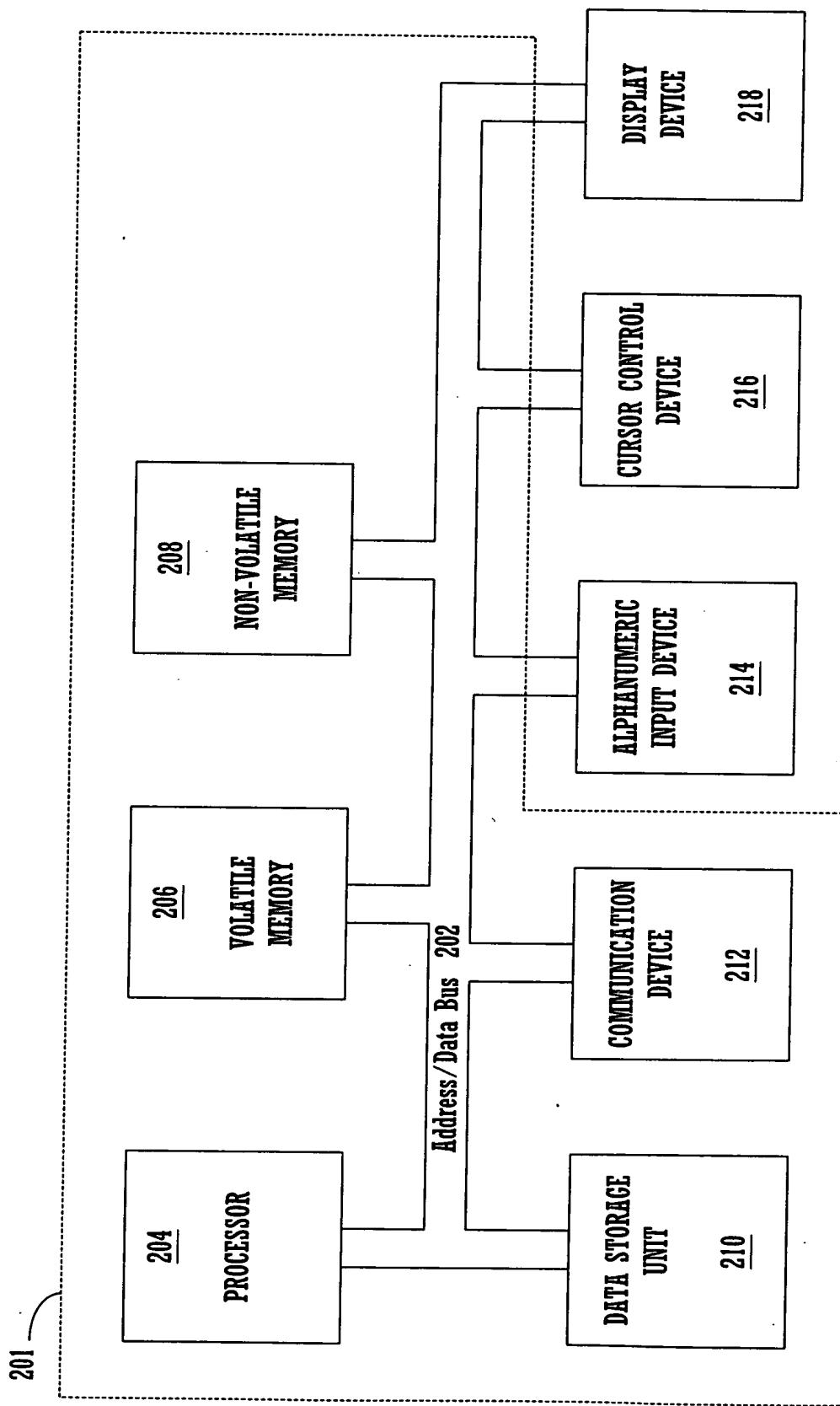
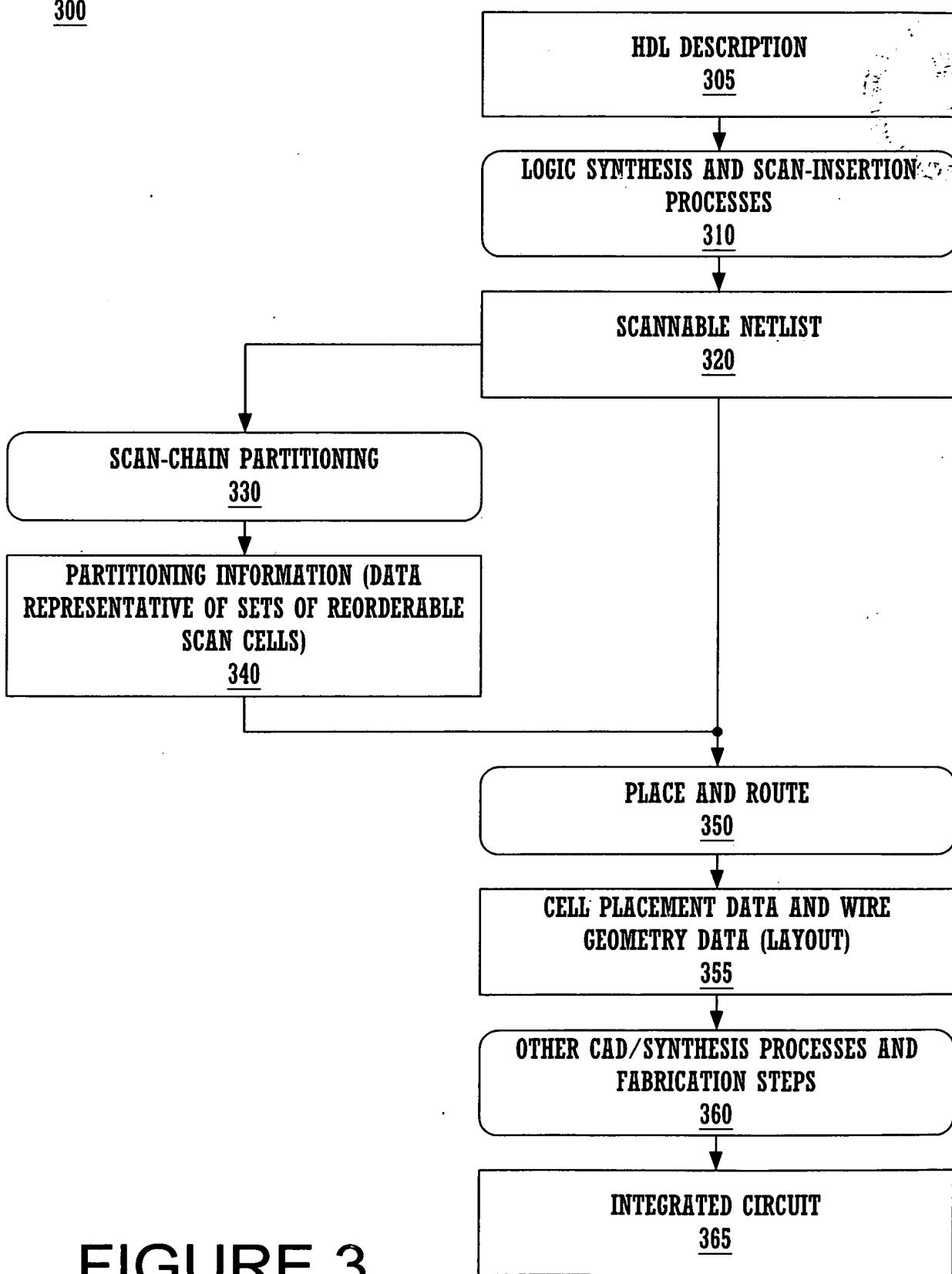


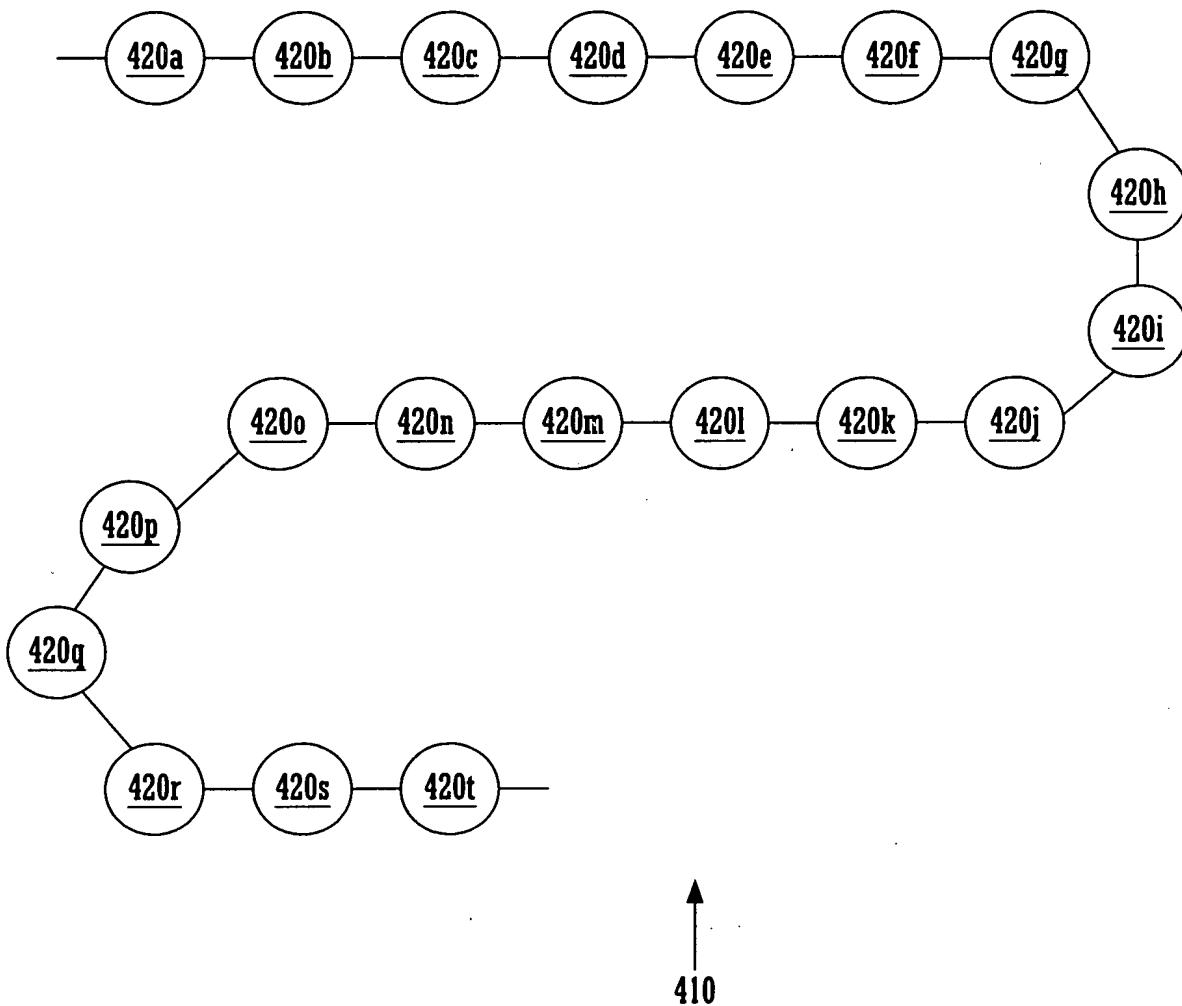
FIGURE 2



**FIGURE 3**

TITLE: SYSTEM AND METHOD FOR HIGH-LEVEL TEST PLANNING FOR LAYOUT  
INVENTOR(S): Suryanarayana Duggirala, Rohit Kapur, Thomas W. Williams  
Attorney Docket #: SNSY-A1998-035

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**FIGURE 4A**

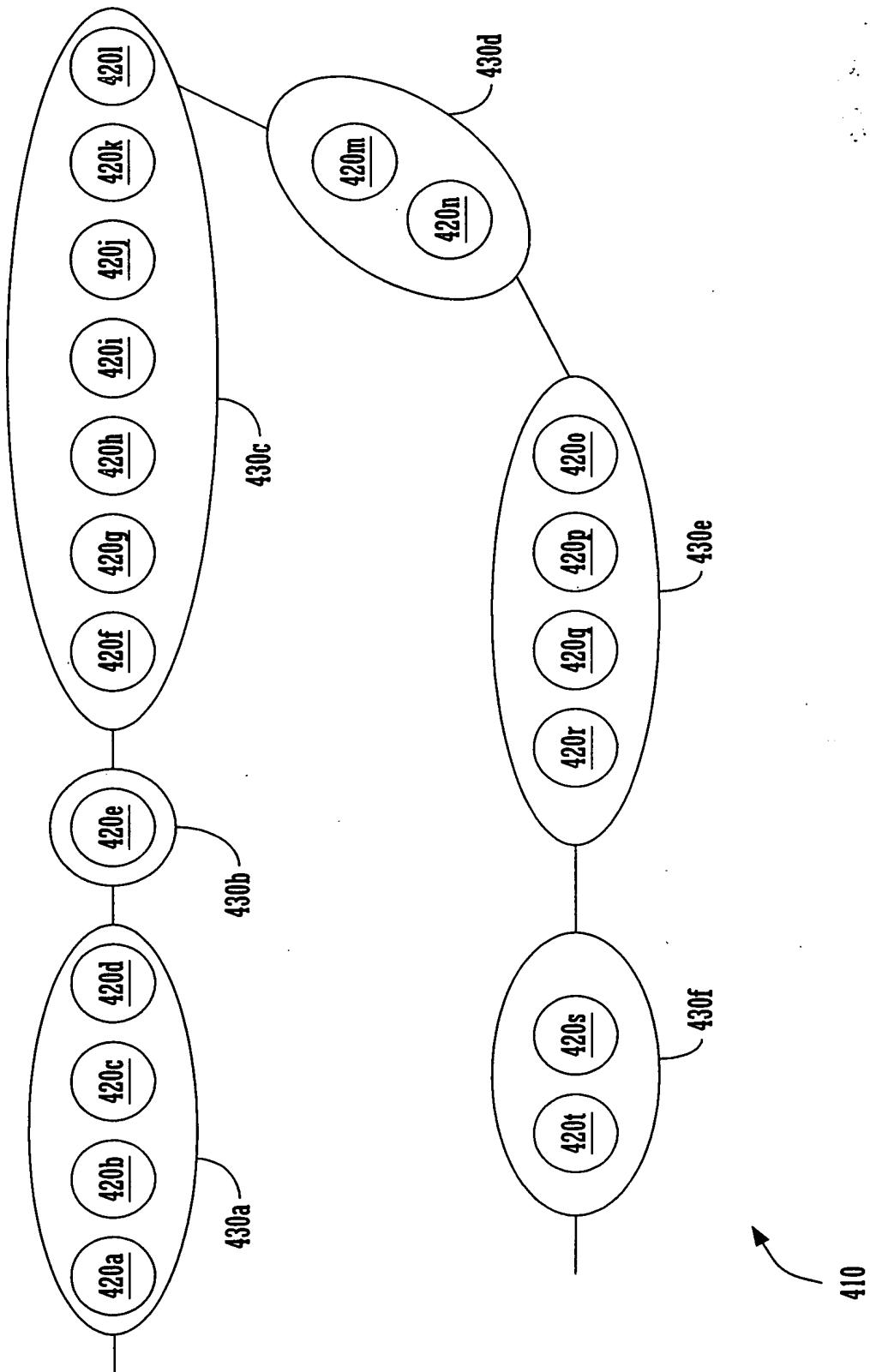
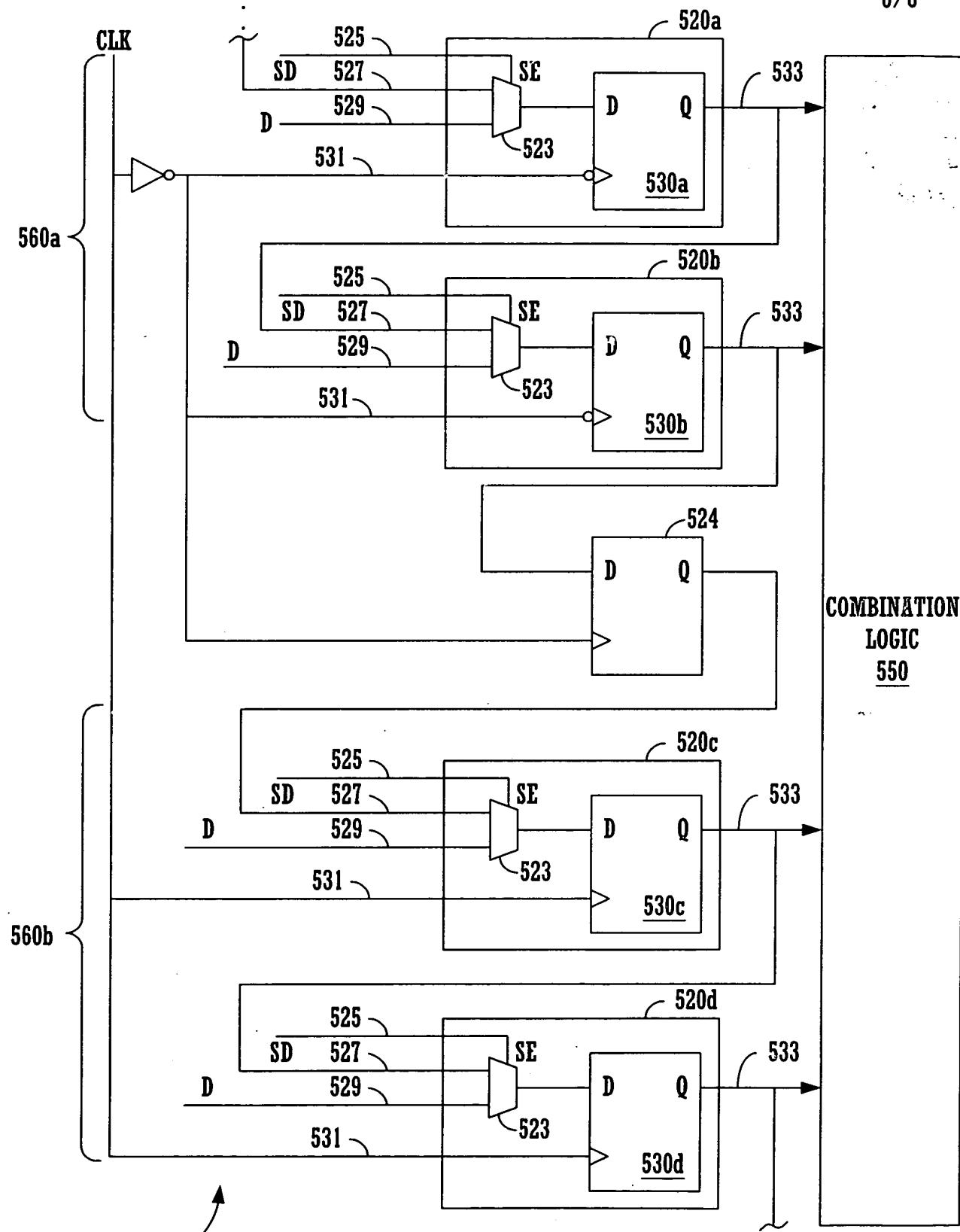


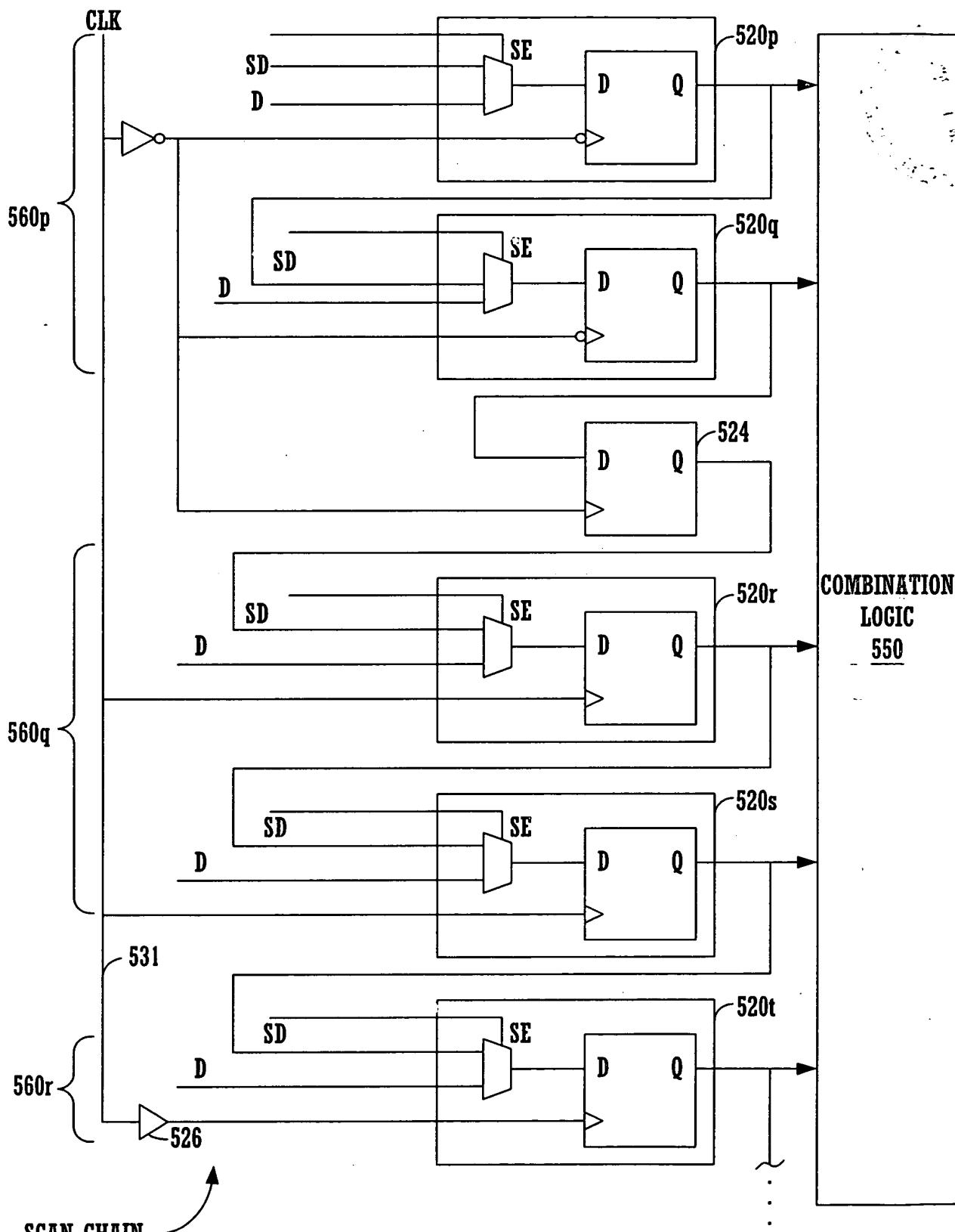
FIGURE 4B



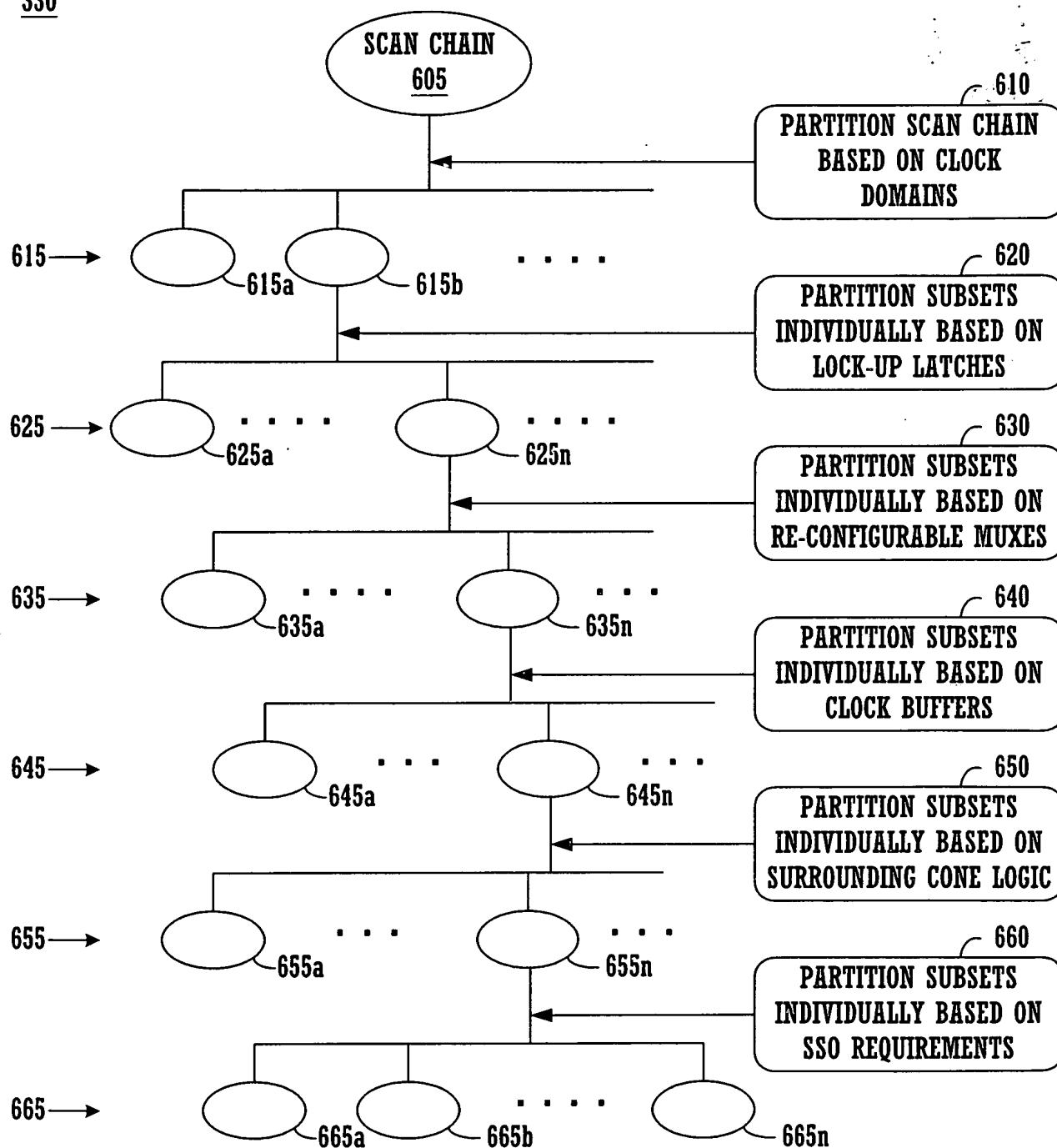
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FIGURE 5A



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**FIGURE 6**